# IGBT Power Module 1200V/300A

### Preliminary

### **Features**

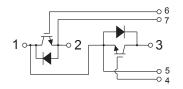
- 62mm Fast Switching / Trench Field Stop IGBT Technology
- ◆ Low Switching Losses
- Super Fast Diodes
- ♦ High Short Circuit Capability

### **Applications**

- Welder / Power Supply
- UPS / Inverter
- ◆ Industrial Motor Drive

# HDA-10662

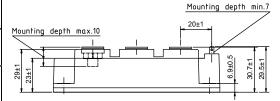
### **Circuit Diagram Headline**

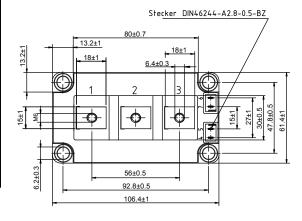


### **Maximum Ratings** ( $Tc = 25^{\circ}C$ )

	Symbol	Rated Value	Unit		
Collector-Emitter	TvJ = 25°C	VCES	1200	V	
Gate-Emitter Peak	Voltage	VGES	±20	V	
Continuous DC Collector Current $T_c = 80$ °C $T_c = 25$ °C				300 450	Α
Repetitive Peak Collector Current tp =1ms				600	Α
Total Power Dissip	Ptot	1600	W		
Isolation Voltage	Viso	2500	V		
Temperature Unde	TVJ op	-40~+150	°C		
Storage Temperat	ure	Tstg	-40~+125	°C	
Mounting Torque	Module Base to Heatsink (M6)			3~6	N.m
Mounting Torque	Busbar to Termir	nal (M6)		2.5~5	IN.III

### **Package Outlines**





Dimensions in mm (1 mm = 0.0394")

### **Preliminary Data**

## **■ Electrical Characteristics**

Characteristics	Symbol	Test Conditions		Min.	Тур.	Max.	Unit
		I <sub>C</sub> =300A, V <sub>GE</sub> =15V	T <sub>vj</sub> =25°C		1.90	2.15	
Collector-emitter saturation voltage	V <sub>CE sat</sub>	I <sub>C</sub> =300A, V <sub>GE</sub> =15V	T <sub>vj</sub> =125°C		2.00		V
		I <sub>C</sub> =300A, V <sub>GE</sub> =15V	T <sub>vj</sub> =150°C		2.05		
Gate threshold voltage	$V_{GEth}$	I <sub>C</sub> =11.5mA, V <sub>CE</sub> =V <sub>GE</sub> , T <sub>vj</sub> =25°C		5.2	5.8	6.4	٧
Gate charge	$Q_{G}$	V <sub>GE</sub> = -15 V +15 V			3.6		μC
Input capacitance	C <sub>ies</sub>	f = 1MHz, T <sub>vj</sub> =25°C, V <sub>CE</sub> =25V, V <sub>GE</sub> =0V			52		nF
Output capacitance	C <sub>oes</sub>	f = 1MHz, T <sub>vj</sub> =25°C, V <sub>CE</sub> =25V, V <sub>GE</sub> =0V			1.3		nF
Reverse transfer capacitance	C <sub>res</sub>	f = 1MHz, T <sub>vj</sub> =25°C, V <sub>CE</sub> =25V, V <sub>GE</sub> =0V			0.7		nF
Collector-emitter cut-off current	I <sub>CES</sub>	V <sub>CE</sub> =1200V, V <sub>GE</sub> =0V, T <sub>vj</sub> =25°C				5	mA
Gate-emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =20V, T <sub>vj</sub> =25°C				400	nA
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V	T <sub>vj</sub> =25°C		0.24		
Turn-on delay time, inductive load	t <sub>d on</sub>	V <sub>GE</sub> = ±15V	T <sub>vj</sub> =125°C		0.31		μs
		$R_{Gon} = 1.3\Omega$	T <sub>vj</sub> =150°C		0.32		
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V	T <sub>vj</sub> =25°C		0.08		
Rise time, inductive load	t <sub>r</sub>	V <sub>GE</sub> = ±15V	T <sub>vj</sub> =125°C		0.075		μs
		$R_{Gon} = 1.3\Omega$	T <sub>vj</sub> =150°C		0.08		
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V	T <sub>vj</sub> =25°C		0.40		
Turn-off delay time, inductive load	t <sub>d off</sub>	V <sub>GE</sub> = ±15V	T <sub>vj</sub> =125°C		0.43		μs
		$R_{Goff} = 1.3\Omega$	T <sub>vj</sub> =150°C		0.45		
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V	T <sub>vj</sub> =25°C		0.08		
Fall time, inductive load	t <sub>f</sub>	V <sub>GE</sub> = ±15V	T <sub>vj</sub> =125°C		0.13		μs
		$R_{Goff} = 1.3\Omega$	T <sub>vj</sub> =150°C		0.15		
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V, L <sub>S</sub> =30nH	T <sub>vj</sub> =25°C		14.5		
Turn-on energy loss per pulse	E <sub>on</sub>	$V_{GE} = \pm 15V$ , di/dt =6000A/ $\mu$ s ( $T_{vj} = 150$ °C)	T <sub>vj</sub> =125°C		23.0		mJ
		$R_{Gon} = 1.3\Omega$	T <sub>vj</sub> =150°C		28.0		
		I <sub>C</sub> =300A, V <sub>CE</sub> =600V, L <sub>S</sub> =30nH	T <sub>vj</sub> =25°C		24.5		
Turn-off energy loss per pulse	E <sub>off</sub>	V <sub>GE</sub> = ±15V, du/dt =4500V/μs (T <sub>vj</sub> =150°C)	T <sub>vj</sub> =125°C		34.5		mJ
		$R_{Goff} = 1.3\Omega$	T <sub>vj</sub> =150°C		37.5		
SC data		V <sub>GE</sub> ≤15V, V <sub>CC</sub> =900V	t <sub>P</sub> ≤10μs,		1200		^
SC data	I <sub>SC</sub>	V <sub>CEmax</sub> =V <sub>CES</sub> - L <sub>sCE</sub> ·di/dt	T <sub>vj</sub> =125°C		1200		Α
Thermal resistance, junction to case	R <sub>thJC</sub>	per IGBT				0.093	°C/W
Thermal resistance, case to heatsink	R <sub>thCH</sub>	per IGBT			0.032		°C/W

### **Preliminary Data**

# Diode Ratings & Characteristics

Characteristics	Symbol	Test Conditions	Value	Unit
Repetitive peak reverse voltage	V <sub>RRM</sub>	T <sub>vj</sub> =25°C	1200	V
Continuous DC forward current	I <sub>F</sub>		300	Α
Repetitive peak forward current	I <sub>FRM</sub>	t <sub>P</sub> =1ms	600	Α
l²t - value		$V_R = 0V, t_P = 10 \text{ms}, T_{yj} = 125^{\circ}\text{C}$	19000	A2a
		$V_R = 0V$ , $t_P = 10ms$ , $T_{ij} = 150$ °C	18000	A²s

Characteristics	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
		$I_F = 300A$ , $V_{GE} = 0V$ $T_{vj} = 25^{\circ}C$		1.9	2.35	
Forward voltage	V <sub>F</sub>	$I_{F} = 300A, V_{GE} = 0V$ $T_{vj} = 125^{\circ}C$		1.9		V
		$I_F = 300A, V_{GE} = 0V$ $T_{vj} = 150^{\circ}C$		1.9		
	I <sub>RM</sub>	$I_F = 300A, -di_F/dt = 6000A/\mu s (T_{vj} = 150^{\circ}C)$ $T_{vj} = 25^{\circ}C$		164		
Peak reverse recovery current		$V_R = 600V$ $T_{vj} = 125^{\circ}C$		228		Α
		$V_{GE} = -15V$ $T_{vj} = 150^{\circ}C$		238		
Recovered charge		$I_F = 300A$ , $-di_F/dt = 6000A/\mu s (T_{vj} = 150^{\circ}C)$ $T_{vj} = 25^{\circ}C$		25		
	Qr	$V_R = 600V$ $T_{vj} = 125^{\circ}C$		42		μC
		$V_{GE} = -15V$ $T_{vj} = 150^{\circ}C$		61		
		$I_F = 300A$ , $-di_F/dt = 6000A/\mu s (T_{vj} = 150^{\circ}C)$ $T_{vj} = 25^{\circ}C$		14.8		
Reverse recovery energy	Erec	$V_R = 600V$ $T_{vj} = 125^{\circ}C$		28		mJ
		$V_{GE} = -15V$ $T_{vj} = 150^{\circ}C$		30.5		
Reverse Recovery Time	Trr	$I_F$ =300A, -di <sub>F</sub> /dt =6000A/ $\mu$ s, $V_R$ =600V, $V_{GE}$ = -15V, $T_{vj}$ =25°C		246		ns
Thermal resistance, junction to case	R <sub>thJC</sub>	per diode			0.15	°C/W
Thermal resistance, case to heatsink	R <sub>thCH</sub>	per diode		0.052		°C/W
Temperature under switching conditions	T <sub>vj op</sub>		-40		150	°C

# **- Module Ratings & Characteristics**

Characteristics	Symbol	Test Conditions	Value	Unit	
Material of module baseplate			Cu		
Internal isolation		basic insulation (class 1, IEC 61140)	$Al_2O_3$		
Out on the state of the state o		terminal to heatsink	29		
Creepage distance		terminal to terminal	23	mm	
Clearance		terminal to heatsink	23		
		terminal to terminal	11	mm	
Comperative tracking index	СТІ		>400		

### **Typical Characteristics**

### **Preliminary Data**

Fig.1 Output characteristic IGBT,Inverter (typical)

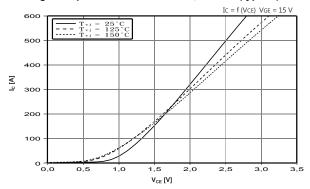


Fig.3 Transfer characteristic IGBT, Inverter (typical)

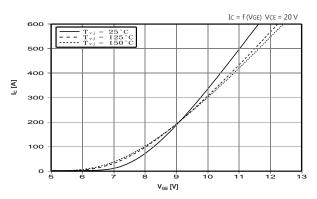


Fig.5 Switching losses IGBT,Inverter (typical)

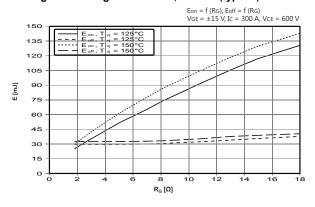


Fig.7 Reverse bias safe operating area IGBT,Inverter

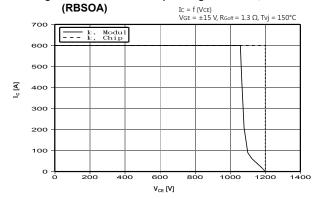


Fig.2 Output characteristic IGBT,Inverter (typical)

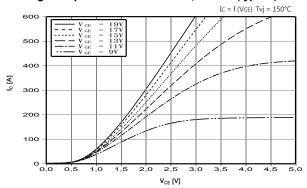


Fig.4 Switching losses IGBT,Inverter (typical)

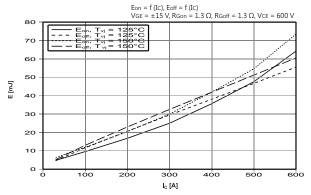


Fig.6 Transient thermal impedance IGBT, Inverter

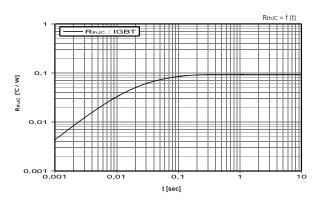
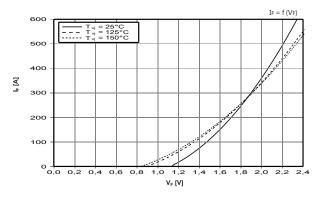


Fig.8 Forward characteristic of Diode, Inverter (typical)



### **Typical Characteristics**

### **Preliminary Data**

### Fig.9 Switching losses Diode, Inverter (typical)

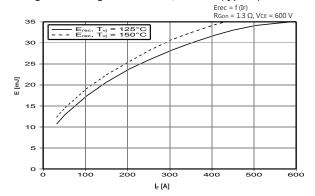


Fig.11 Transient thermal impedance Diode, Inverter

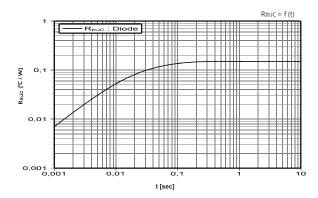
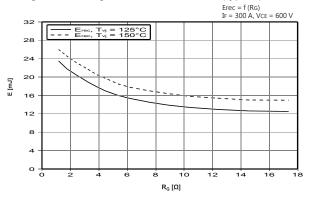


Fig.10 Switching losses Diode, Inverter (typical)





### Disclaimer

DACO Semiconductor reserves the right to make modifications, enhancements, improvements, corrections, or other changes to this document and any product described herein without prior notice.

DACO Semiconductor makes no warranty, representation, or guarantee regarding the suitability of its products for any particular purpose, nor does DACO Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any liability, including without limitation special, consequential or incidental damages.

Purchasers are responsible for its products and applications using DACO Semiconductor products, including compliance with all laws, regulations, and safety requirements or standards, regardless of any support or application information provided by DACO Semiconductor. "Typical" parameters that may be provided in DACO Semiconductor datasheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typical" must be validated for each customer application by the customer's technical experts.

DACO Semiconductor products are not designed, authorized, or warranted to be suitable for use in life support, life-critical or safety-critical systems, or equipment. nor in applications where failure or malfunction of DACO Semiconductor's product can reasonably be expected to result in personal injury, death or severe property or environmental damage. DACO Semiconductor accepts no liability for the inclusion and/or use of DACO Semiconductor's products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Purchasers who buy or use DACO Semiconductor products for any unintended or unauthorized applications are required to indemnify and absolve DACO Semiconductor, its suppliers, and distributors from any claims, costs, damages. expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that DACO Semiconductor was negligent regarding the design or manufacture of the part.

No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or by any information storage and retrieval system, or otherwise, without the prior written permission of DACO Semiconductor Co., Ltd.

www.dacosemi.com.tw